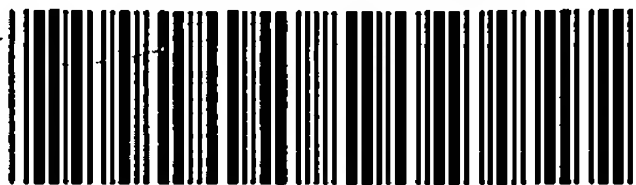


# Search Notes



Application/Control No.

10/630,217

Examiner

David M. Naff

Applicant(s)/Patent under  
Reexamination

BECKER ET AL.

Art Unit

1651

## SEARCHED

Class	Subclass	Date	Examiner

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
09/58/717	2/24/06	an
West	1	1
See printout		